

# Volta Series Probe Specifications

Volta Series Specifications		Volta 180	Volta 200	Volta 250	Volta 300	Volta 350	Volta 400
		**851-0023049-H00	**851-0012074-H01	**851-0023038-H00	*102121-H00	*102119-H00	**102120-H00
Wafer I/O Pitch		180 $\mu\text{m}$	200 $\mu\text{m}$	250 $\mu\text{m}$	300 $\mu\text{m}$	350 $\mu\text{m}$	400 $\mu\text{m}$
Minimum Probe Depth (At Test)		2.85 mm	2.85 mm	2.90 mm	3.80 mm	3.50 mm	2.90 mm
Probe Travel	Wafer Side	230 $\mu\text{m}$	230 $\mu\text{m}$	250 $\mu\text{m}$	250 $\mu\text{m}$	300 $\mu\text{m}$	300 $\mu\text{m}$
	PCB Side	170 $\mu\text{m}$	170 $\mu\text{m}$	150 $\mu\text{m}$	150 $\mu\text{m}$	150 $\mu\text{m}$	150 $\mu\text{m}$
Spring Material		music wire	music wire	music wire	stainless steel	stainless steel	stainless steel
Device Side Contact Material		Homogenous					
Probe Tip Shape		4-Point Crown					
Spring Force		6.5 gf	10 gf	15 gf	17.5 gf	16 gf	17 gf
Contact Resistance		< 200 m $\Omega$	< 250 m $\Omega$	< 100 m $\Omega$	< 100 m $\Omega$	< 70 m $\Omega$	< 50 m $\Omega$
Continuous Current Carrying Capacity (Room Temp.)		0.84A	1.2A	1.5A	2A	2.50A	3A
Insertion Loss (Pattern: R-S-R @ -1 dB)		20 GHz	22 GHz	30 GHz	20 GHz	20 GHz	20 GHz
Loop Inductance		0.65 nH	0.56 nH	0.76 nH	0.95 nH	0.92 nH	0.82 nH
Capacitance		0.40 pF	0.22 pF	0.31 pF	0.39 pF	0.41 pF	0.30 pF
Working Temperature		-55° to 120°C	-55° to 120°C	-55° to 120°C	-55° to 150°C	-55° to 150°C	-55° to 150°C
Max. Number of Test Sites		Defined by the FEA [Total pin count at a defined area is the limit]					
Sorted Die Test Feature (Alignment Plate and Manual Actuator)		Yes	Yes	Yes	Yes	Yes	Yes
Individual Contact Replacement		Yes	Yes	Yes	Yes	Yes	Yes

Notes:

\* Suitable for engineering plastic and machined ceramic

\*\* Suitable for engineering plastic only